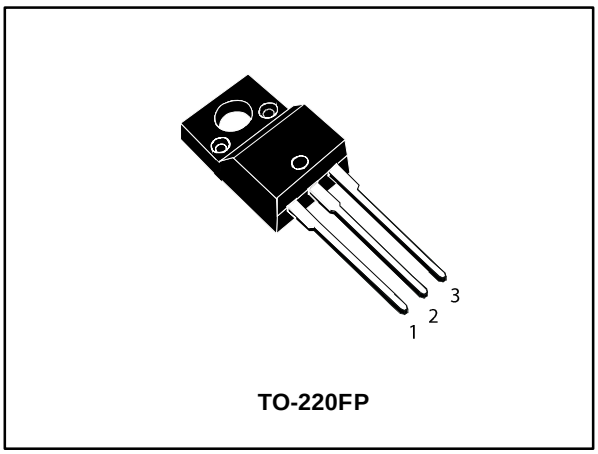
STF4LN80K5

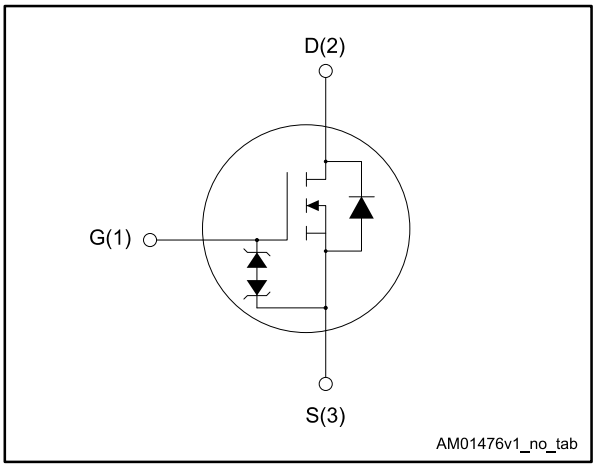
N-channel 800 V, 2.1 Ω typ., 3 A MDmesh™ K5 Power MOSFET in a TO-220FP package

Datasheet - production data



TO-220FP

Figure 1: Internal schematic diagram



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STF4LN80K5	800 V	2.6 Ω	3 A

- Industry's lowest $R_{DS(on)}$ * area
- Industry's best FoM (figure of merit)
- Ultra low-gate charge
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Table 1: Device summary

Order code	Marking	Package	Packing
STF4LN80K5	4LN80K5	TO-220FP	Tube

Contents

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 30	V
I_D(1)	Drain current (continuous) at T_C = 25 °C	3	A
I_D(1)	Drain current (continuous) at T_C = 100 °C	1.9	A
I_D(2)	Drain current pulsed	12	A
P_{TOT}	Total dissipation at T_C = 25 °C	20	W
V_{iso}	Insulation withstand voltage (RMS) from all three leads to external heat sink. (t = 1 s; T_C = 25 °C)	2500	V
dv/dt(3)	Peak diode recovery voltage slope	15	V/ns
dv/dt(4)	MOSFET dv/dt ruggedness	50	
T_j	Operating junction temperature range	- 55 to 150	°C
T_{stg}	Storage temperature range		

Notes:

(1)Limited by maximum junction temperature.

(2)Pulse width limited by safe operating area

(3)I_{SD}≤ 3 A, di/dt≤100 A/µs; V_{DS} peak ≤ $V_{(BR)DSS}$, V_{DD} = 400 V.

(4)V_{DS} ≤ 640 V

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case	6.25	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient	62.5	°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by Tjmax)	0.8	A
E_{AS}	Single pulse avalanche energy (starting Tj = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	160	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 5: On/off-state

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	800			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 800 V			1	µA
		V_{GS} = 0 V, V_{DS} = 800 V T_C = 125 °C(1)			50	µA
I_{GSS}	Gate body leakage current	V_{DS} = 0 V, V_{GS} = ± 20 V			± 10	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 100 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 1 A		2.1	2.6	Ω

Notes:

(1) Defined by design, not subject to production test.

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	122	-	pF
C_{oss}	Output capacitance		-	11	-	pF
C_{rss}	Reverse transfer capacitance		-	0.3	-	pF
$C_{o(tr)}$(1)	Equivalent capacitance time related	V_{DS} = 0 to 640 V, V_{GS} = 0 V	-	23	-	pF
$C_{o(er)}$(2)	Equivalent capacitance energy related		-	9	-	pF
R_g	Intrinsic gate resistance	f = 1 MHz ,I_D = 0 A	-	18	-	Ω
Q_g	Total gate charge	V_{DD} = 640 V, I_D = 2.5 A V_{GS}= 10 V, see *Figure 15: "Test circuit for gate charge behavior"*	-	3.7	-	nC
Q_{gs}	Gate-source charge		-	1	-	nC
Q_{gd}	Gate-drain charge		-	2.2	-	nC

Notes:

(1) Time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

(2) Energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD}= 400 V, I_D = 1.25 A, R_G = 4.7 Ω V_{GS} = 10 V, see *Figure 14: "Test circuit for resistive load switching times"* and *Figure 19: "Switching time waveform"*	-	7	-	ns
t_r	Rise time		-	9	-	ns
$t_{d(off)}$	Turn-off delay time		-	31	-	ns
t_f	Fall time		-	25	-	ns

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		3	A
I_{SDM}(1)	Source-drain current (pulsed)		-		12	A
V_{SD}(2)	Forward on voltage	I_{SD} = 2.5 A, V_{GS} = 0 V	-		1.5	V
t_{rr}	Reverse recovery time	I_{SD} = 2.5 A, di/dt = 100 A/µs, V_{DD} = 60 V, see *Figure 16: "Test circuit for inductive load switching and diode recovery times"*	-	230		ns
Q_{rr}	Reverse recovery charge		-	1.04		µC
I_{RRM}	Reverse recovery current		-	9		A
t_{rr}	Reverse recovery time	I_{SD} = 2.5 A, di/dt = 100 A/µs, V_{DD} = 60 V, T_j = 150 °C, see *Figure 16: "Test circuit for inductive load switching and diode recovery times"*	-	368		ns
Q_{rr}	Reverse recovery charge		-	1.53		µC
I_{RRM}	Reverse recovery current		-	8		A

Notes:

(1)Pulse width limited by safe operating area

(2)Pulsed: pulse duration = 300 µs, duty cycle 1.5%

Table 9: Gate-source Zener diode

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	I_{GS} = ± 1 mA, I_D = 0 A	30	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

2.1 Electrical characteristics (curves)

Figure 2: Safe operating area

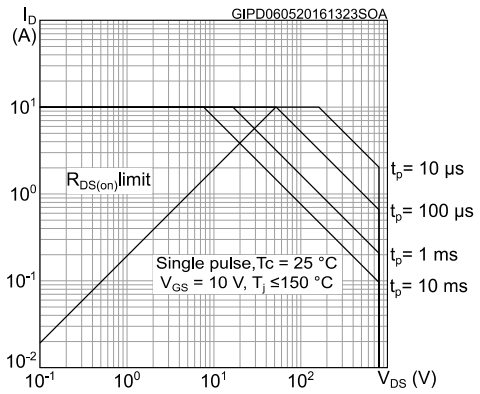


Figure 3: Thermal impedance

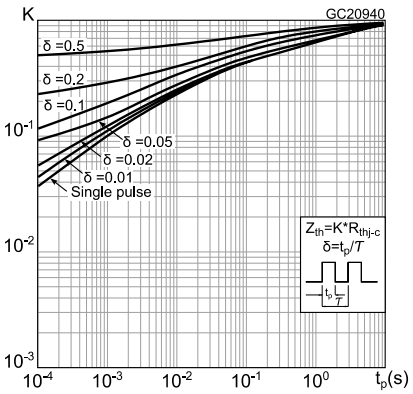


Figure 4: Output characteristics

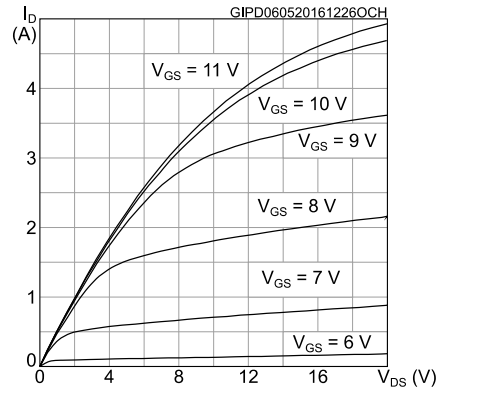


Figure 5: Transfer characteristics

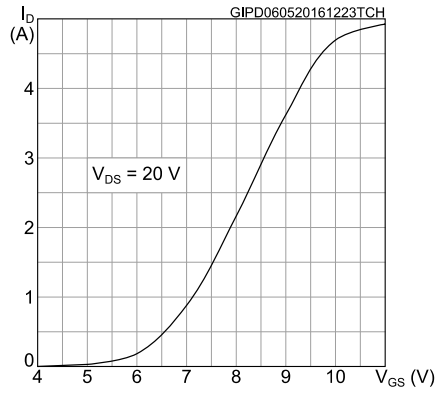


Figure 6: Gate charge vs gate-source voltage

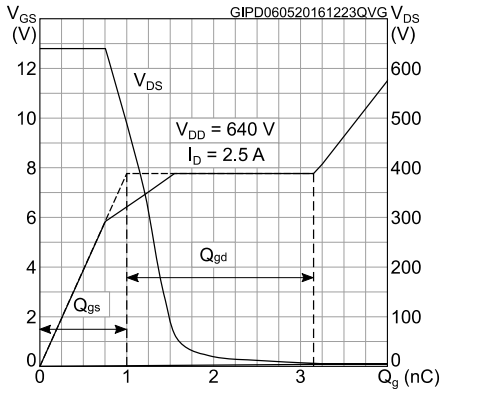


Figure 7: Static drain-source on-resistance

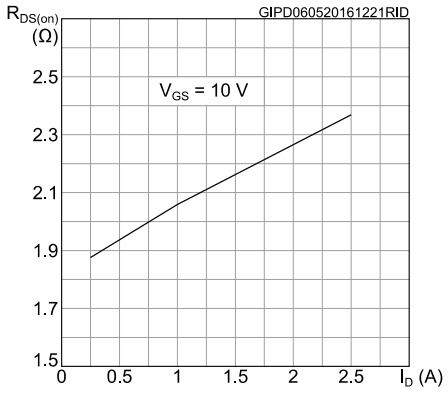


Figure 8: Capacitance variations

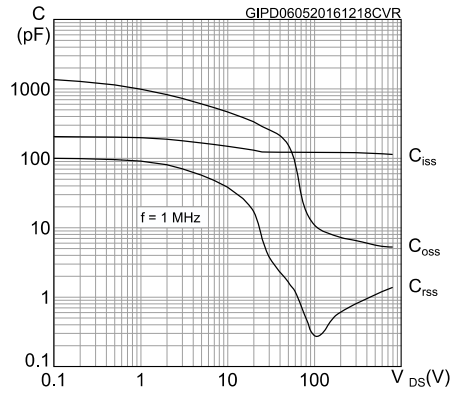


Figure 9: Normalized gate threshold voltage vs temperature

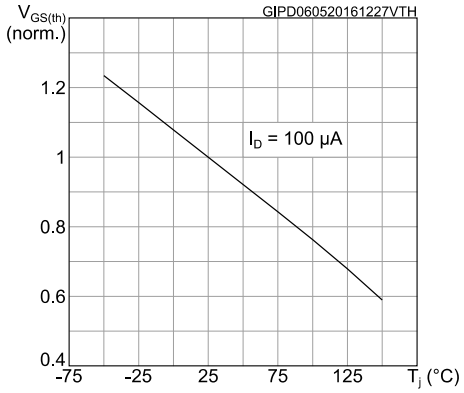


Figure 10: Normalized on-resistance vs temperature

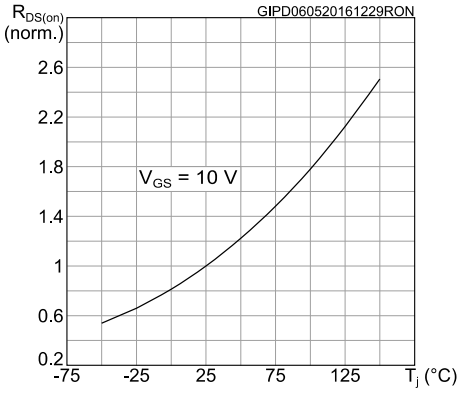


Figure 11: Normalized $V_{(BR)DSS}$ vs temperature

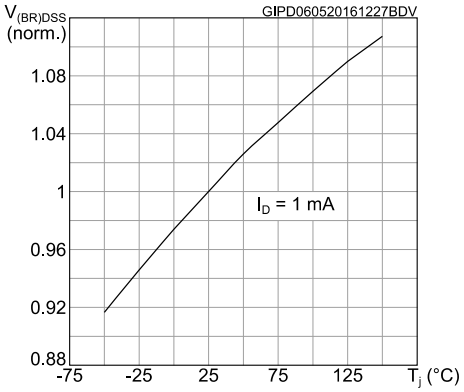


Figure 12: Maximum avalanche energy vs starting T_J

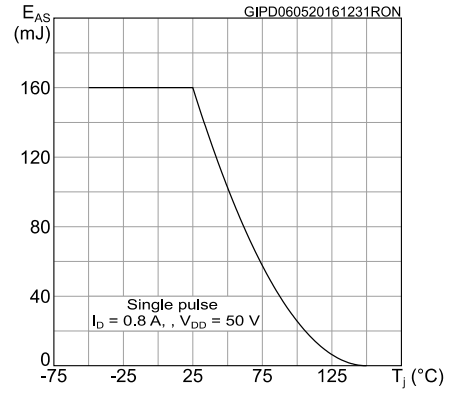
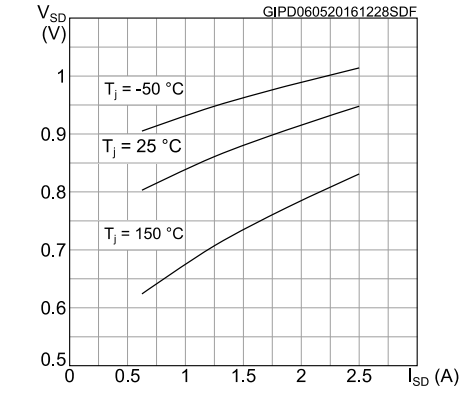


Figure 13: Source-drain diode forward characteristics



3 Test circuits

Figure 14: Test circuit for resistive load switching times

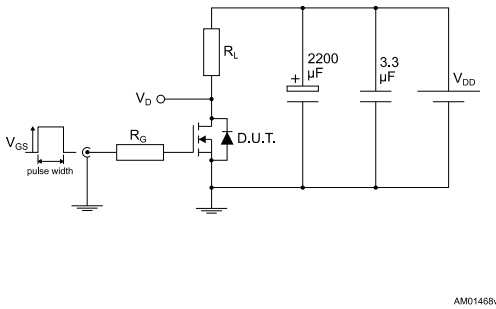


Figure 15: Test circuit for gate charge behavior

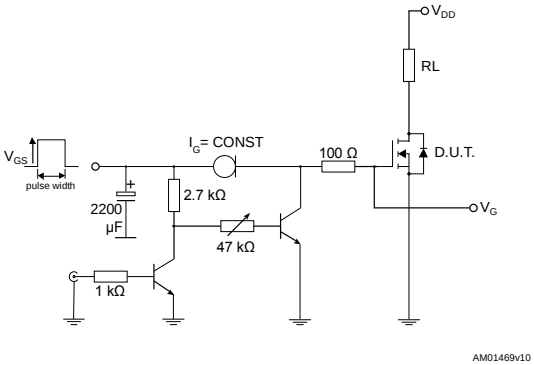


Figure 16: Test circuit for inductive load switching and diode recovery times

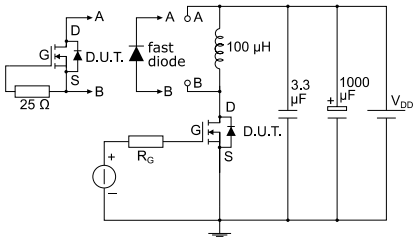


Figure 17: Unclamped inductive load test circuit

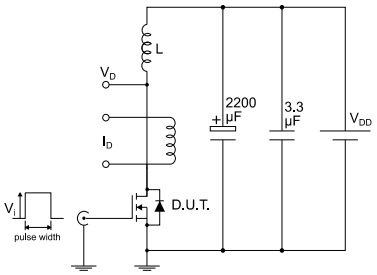


Figure 18: Unclamped inductive waveform

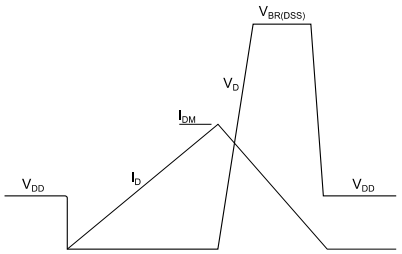
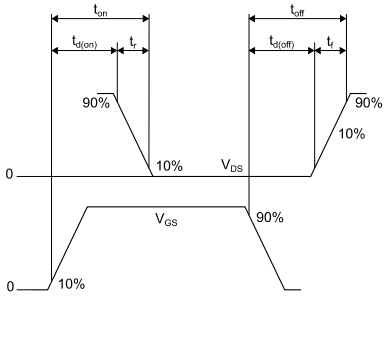


Figure 19: Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: ***www.st.com***. ECOPACK® is an ST trademark.

4.1 TO-220FP package information

Figure 20: TO-220FP package outline

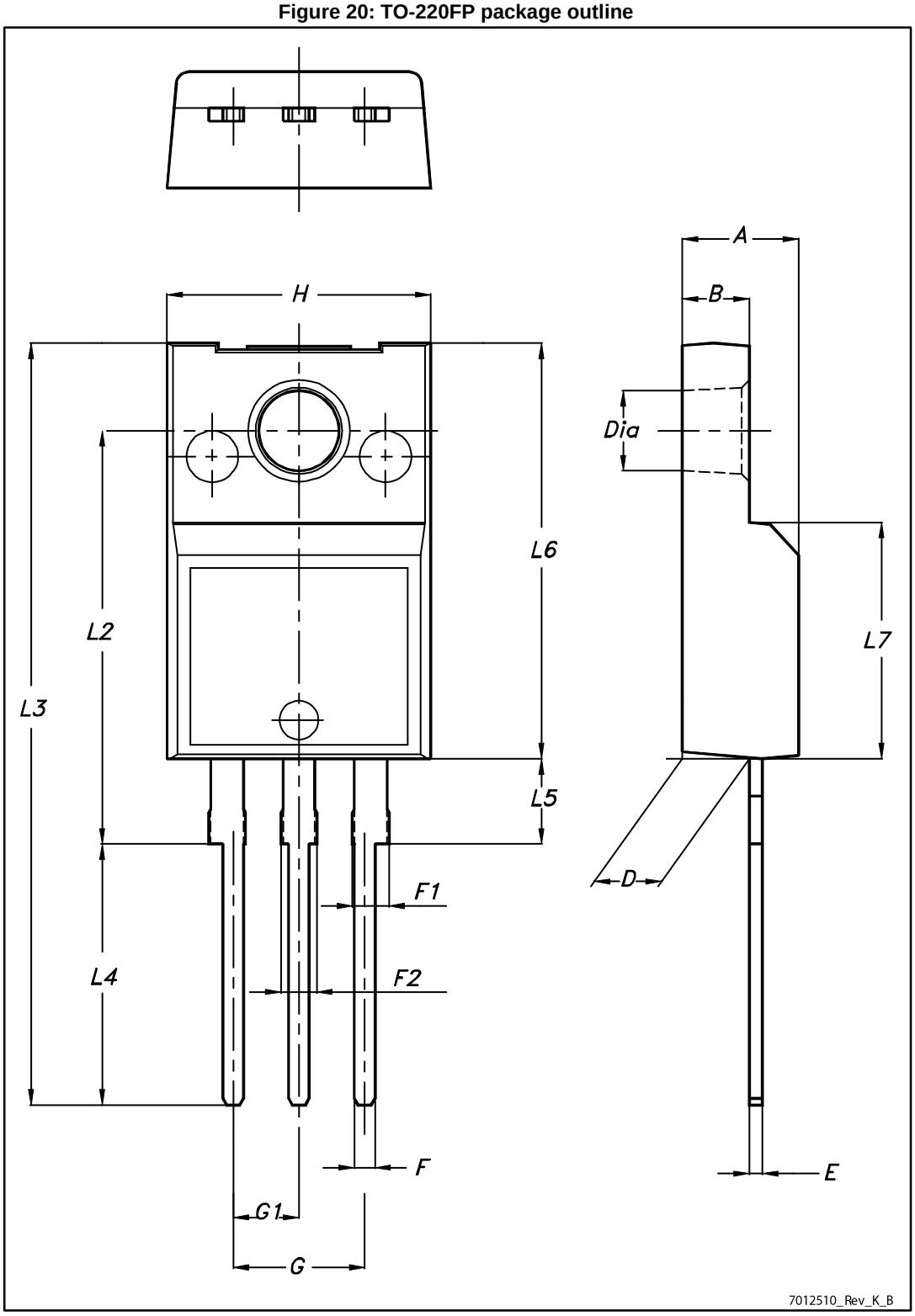


Table 10: TO-220FP package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

5 Revision history

Table 11: Document revision history

Date	Revision	Changes
04-Jun-2015	1	First release.
18-May-2016	2	Document status promoted from preliminary data to production data. Updated *Figure 1: "Internal schematic diagram"*. Updated *Section 1: "Electrical ratings", Section 2: "Electrical characteristics".* Added *Section 2.1: "Electrical characteristics (curves)".* Updated *Section 3: "Test circuits"*. Minor text changes.

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